











LMX2492, LMX2492-Q1

ZHCSCB6-MARCH 2014

LMX2492/LMX2492-Q1 14GHz 低噪声分数 N 分频锁相环 (PLL), 坡/超宽带信号源发生功能

特性

- -227dBc/Hz 标称 PLL 噪声
- 500MHz 14GHz 宽频带 PLL
- 3.15 -5.25V 电荷泵 PLL 电源
- 多用途斜坡/超宽带信号源发生
- 最大相位检测器频率 200MHz
- 频移键控/相移键控 (FSK/PSK) 调制引脚
- 数字锁检测
- 单个 3.3V 电源
- 汽车用 125°C Q100 1 级认证
- 非汽车用 (LMX2492) 选项

2 应用范围

- 汽车用调频连续波 (FMCW) 雷达
- 军用雷达
- 微波回程
- 测试和测量
- 卫星通信
- 无线基础设施
- 针对高速模数转换器 (ADC) / 数模转换器 (DAC) 的 采样时钟

3 说明

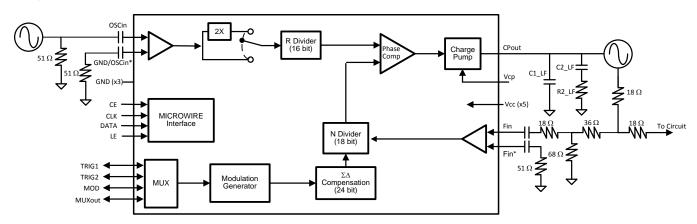
LMX2492/92-Q1 是一款具有斜坡和超宽带信号源发生 功能的 14GHz 宽频带三角积分分数 N 分频 PLL。 它 由一个相位频率检测器、可编程电荷泵以及用于外部 VCO 的高频输入组成。 LMX2492/92-Q1 支持宽范围 且灵活的斜升功能类 (class of ramping capabilities), 其中包括 FSK, PSK 和高达 8 个段的可配置分段线性 FM 调制系统配置。 它还支持精细的 PLL 分辨率以及 相位检测器速率高达 200MHz 的快速斜坡。 LMX2492/92-Q1 的任何一个寄存器均可被回读。 LMX2492/92-Q1 可由单个 3.3V 电源供电运行。 而

目,对于电压高达 5.25V 的电荷泵的支持能够免除对 于外部放大器的需要,从而获得一个具有更佳相位噪声 性能的更简单解决方案。

器件信息

订货编号	封装	封装尺寸
LMX2492-Q1RTW	超薄四方扁平无	
LMX2492RTW	引线 (WQFN) (24)	4mm x 4mm

简化电路原理图



www.ti.com.cn

目录

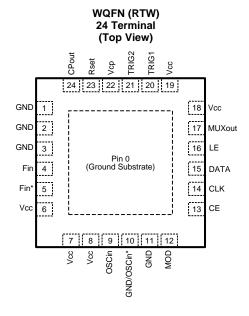
	4.+. kd.		9.6. Degister Men	4.4
1	特性		8.6 Register Map	
2	应用范围 1		8.7 Register Field Descriptions	
3	说明 1		8.8 Lock Detect and Charge Pump Monitoring	
4	简化电路原理图1		8.9 TRIG1,TRIG2,MOD, and MUXout Pins	22
5	修订历史记录 2		8.10 Ramping Functions	
6	Terminal Configuration and Functions		8.11 Individual Ramp Controls	26
	_	9	Applications and Implementation	27
7	Specifications4		9.1 Application Information	27
	7.1 Absolute Maximum Ratings		9.2 Typical Applications	
	7.2 Handling Ratings4	10	Power Supply Recommendations	
	7.3 Recommended Operating Conditions4	11	Layout	
	7.4 Thermal Information4			
	7.5 Electrical Characteristics 5		,	
	7.6 Timing Requirements, Programming Interface (CLK,		11.2 Layout Example	
	DATA, LE)6	12	Device and Documentation Support	
	7.7 Serial Data Input Timing 6		12.1 Device Support	35
	7.8 Typical Characteristics		12.2 Documentation Support	35
8	Detailed Description9		12.3 Related Links	35
	8.1 Overview 9		12.4 Trademarks	35
	8.2 Functional Block Diagram9		12.5 Electrostatic Discharge Caution	35
	8.3 Feature Description9		12.6 Glossary	35
	8.4 Device Functional Modes	13	机械封装和可订购信息	35
	8.5 Programming		P = 5/4 - 4 - 4 - 4 - 4 - 4 - 4 - 4 - 4 - 4 -	
	0.0 1 Togramming			

5 修订历史记录

日期	修订版本	注释
2014年3月	*	最初发布版本。

www.ti.com.cn ZHCSCB6 – MARCH 2014

6 Terminal Configuration and Functions



Terminal Functions

TERMINAL NUMBER NAME		TVDE	DECORPTION		
		TYPE	DESCRIPTION		
0	DAP	GND	Die Attach Pad. Connect to PCB ground plane.		
1	GND	GND	Ground for charge pump.		
2,3	GND	GND	Ground for Fin Buffer		
4,5	Fin Fin*	Input	Complimentary high frequency input pins. Should be AC coupled. If driving single-ended, impedance as seen from Fin and Fin* pins looking outwards from the part should be roughly same.		
6	Vcc	Supply	Power Supply for Fin Buffer		
7	Vcc	Supply	Supply for On-chip LDOs		
8	Vcc	Supply	Supply for OSCin Buffer		
9	OSCin	Input	Reference Frequency Input		
10	GND/ OSCin*	GND/Input	Complimentary input for OSCin. If not used, it is recommended to match the termination as seen from the OSCin terminal looking outwards. However, this may also be grounded as well.		
11	GND	GND	Ground for OSCin Buffer		
12	MOD	Input/Output	Multiplexed Input/Output Pins for Ramp Triggers, FSK/PSK Modulation, FastLock, and Diagnostics		
13	CE	Input	Chip Enable		
14	CLK	GND	Serial Programming Clock.		
15	DATA	GND	Serial Programming Data		
16	LE	Input	Serial Programming Latch Enable		
17	MUXout	Input/Output	Multiplexed Input/Output Pins for Ramp Triggers, FSK/PSK Modulation, FastLock, and Diagnostics		
18	Vcc	Supply	Supply for delta sigma engine.		
19	Vcc	Supply	Supply for general circuitry.		
20	TRIG1	Input/Output	Multiplexed Input/Output Pins for Ramp Triggers, FSK/PSK Modulation, FastLock, and Diagnostics		
21	TRIG2	Input/Output	Multiplexed Input/Output Pins for Ramp Triggers, FSK/PSK Modulation, FastLock, and Diagnostics		
22	Vcp	Supply	Power Supply for the charge pump.		
23	Rset	NC	No connect.		
24	CPout	Output	Charge Pump Output		



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
Vcp	Supply Voltage for Charge Pump	Vcc	5.5	V
CPout	Charge Pump Output Pin	-0.3	Vcp	V
Vcc	All Vcc Pins	-0.3	3.6	V
Others	All Other I/O Pins	-0.3	Vcc + 0.3	V
T _{Solder}	Lead Temperature (solder 4 seconds)		260	°C
T _{Junction}	Junction Temperature		150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 Handling Ratings

		MIN	MAX	UNIT
T _{STG}	Storage Temperature Range	-65	150	°C
MSL	Moisture Sensitivity Level		3	n/a
v (1)	Human body model (HBM) ESD stress voltage (2)		2500	V
V _{ESD} ⁽¹⁾	Charged device model (CDM) ESD stress voltage ⁽³⁾		1500	V

⁽¹⁾ Electrostatic discharge (ESD) to measure device sensitivity and immunity to damage caused by assembly line electrostatic discharges in to the device.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

SYMBOL	PARAMETER	DEVICE	MIN	TYP	MAX	UNIT
Vcc	PLL Supply Voltage		3.15	3.3	3.45	V
Vcp	Charge Pump Supply Voltage		Vcc		5.25	V
_	Ambient Temperature	LMX2492	-40		85	٥°
1A	Ambient Temperature	LMX2492-Q1	-40		125	
_	lunction Townserture	LMX2492	-40		125	°C
IJ	Junction Temperature	LMX2492-Q1	-40		135	°C

7.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	Temperature	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	39.4	
$R_{\theta JC}$	Junction-to-case thermal resistance	7.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	20	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

⁽²⁾ Level listed above is the passing level per ANSI, ESDA, and JEDEC JS-001. JEDEC document JEP155 states that 500 V HBM allows safe manufacturing with a standard ESD control process.

⁽³⁾ Level listed above is the passing level per EIA-JEDEC JESD22-C101. JEDEC document JEP157 states that 250 V CDM allows safe manufacturing with a standard ESD control process.

ZHCSCB6-MARCH 2014 www.ti.com.cn

7.5 Electrical Characteristics

(3.15 V ≤ Vcc ≤ 3.45 V. Vcc ≤Vcp ≤5.25 V. Typical values are at Vcc = Vcp = 3.3 V, 25 °C. -40°C ≤ T_A ≤ 85 °C for the LMX2492 and -40°C ≤ T_A ≤ 125 °C for the LMX2492-Q1; except as specified.)

SYMBOL	PARAMETER	COI	CONDITIONS		TYP	MAX	UNIT	
			Fpd = 10 MHz		45			
		All Vcc Pins	Fpd = 100 MHz		50		mA	
laa	Comment Commenting		Fpd = 200 MHz		55			
Icc	Current Consumption		Kpd = 0.1 mA		2			
		Vcp Pin	Kpd = 1.6 mA		10			
			Kpd = 3.1 mA		19			
IccPD	Current	POWERDOWN			3			
		OSC_DIFFR=0,	Doubler Disabled	10		600		
4	Frequency for OSCin terminal	OSC_DIFFR=0, Doubler Enabled		10		300	MHz	
f _{OSCin}		OSC_DIFFR=1, Doubler Disabled		10		1200		
		OSC_DIFFR=1, Doubler Enabled		10		600		
V _{OSCin}	Voltage for OSCin Pin ⁽¹⁾					Vcc-0.5	Vpp	
f _{Fin}	Frequency for FinPin ⁽²⁾					14000	MHz	
p _{Fin}	Power for Fin Pin	Single-Ended Op	eration	-5		5	dBm	
f_{PD}	Phase Detector Frequency					200	MHz	
PN1Hz	PLL Figure of Merit ⁽³⁾				-227		dBc/Hz	
PN10kHz	Normalized PLL 1/f Noise ⁽³⁾	Normalized to 10 carrier.	kHz offset for a 1 GHz		-120		dBc/Hz	
I _{CPout} TRI	Charge Pump Leakage Tristate Leakage					10	nA	
I _{CPout} MM	Charge Pump Mismatch (4)	V _{CPout} = Vcp / 2			5 %			
			CPG=1X		0.1			
I _{CPout}	Charge Pump Current	V _{CPout} = Vcp / 2					mA	
					3.1			

For optimal phase noise performance, higher input voltage and a slew rate of at least 3 V/ns is recommended

Tested to 13.5 GHz, Guaranteed to 14 GHz by characterization

PLL Noise Metrics are measured with a clean OSCin signal with a high slew rate using a wide loop bandwidth. The noise metrics model the PLL noise for an infinite loop bandwidth as: PLL_Total = 10xlog(10^{PLL_Flat/10} + 10^{PLL_Flicker(Offset)/10})

PLL_Flat = PN1Hz + 20xlog(N) + 10xlog(Fpd/1Hz)
PLL_Flicker = PN10kHz - 10xlog(Offset/10kHz) + 20xlog(Fvco/1GHz)

⁽⁴⁾ Charge pump mismatch varies as a function of charge pump voltage. Consult typical performance characteristics to see this variation.

www.ti.com.cn



Electrical Characteristics (continued)

(3.15 V \leq Vcc \leq 3.45 V. Vcc \leq Vcp \leq 5.25 V. Typical values are at Vcc = Vcp = 3.3 V, 25 °C.

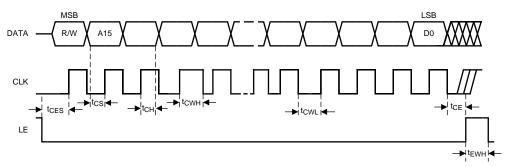
-40°C ≤ T_A ≤ 85 °C for the LMX2492 and -40°C ≤ T_A ≤ 125 °C for the LMX2492-Q1; except as specified.)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
LOGIC OUT	PUT TERMINALS (MUXout,1	RIG1,TRIG2,MOD)				
V _{OH}	Output High Voltage		0.8 x Vcc	Vcc		V
V _{OL}	Output Low Voltage			0	0.2 x Vcc	V
LOGIC INPU	JT TERMINALS (CE,CLK,DA	TA,LE,MUXout,TRIG1,TRIG2,MOD)				
V _{IH}	Input High Voltage		1.4		Vcc	V
V _{IL}	Input Low Voltage		0		0.6	V
I _{IH}	Input Leakage		-5	1	5	uA
T _{CE} LOW	Chip enable Low Time		5			us
T _{CE} HIGH	Chip enable High Time		5			us

7.6 Timing Requirements, Programming Interface (CLK, DATA, LE)

SYMBOL	PARAMETER	MIN	TYP MAX	UNIT
T _{CE}	Clock To LE Low Time	35		ns
T _{CS}	Data to Clock Setup Time	10		ns
T _{CH}	Data to Clock Hold Time	10		ns
T _{CWH}	Clock Pulse Width High	25		ns
T _{CWL}	Clock Pulse Width Low	25		ns
T _{CES}	Enable to Clock Setup Time	10		ns
T _{EWH}	Enable Pulse Width High	10		ns

7.7 Serial Data Input Timing



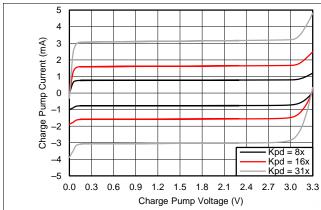
There are several other considerations for programming:

- The DATA is clocked into a shift register on each rising edge of the CLK signal. On the rising edge of the LE signal, the data is sent from the shift register to an actual counter.
- If no LE signal is given after the last data bit and the clock is kept toggling, then these bits will be read into the next lower register. This eliminates the need to send the address each time.
- A slew rate of at least 30 V/us is recommended for the CLK, DATA, and LE signals
- Timing specs also apply to readback. Readback can be done through the MUXout, TRIG1, TRIG2, or MOD terminals.



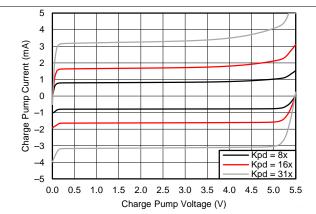
www.ti.com.cn ZHCSCB6 – MARCH 2014

7.8 Typical Characteristics



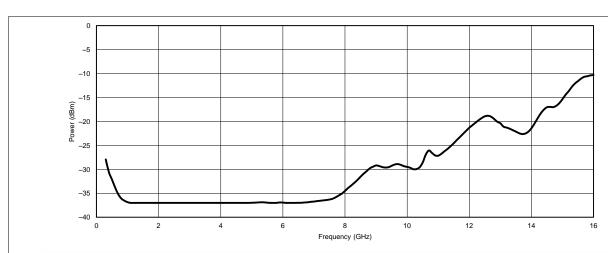
For a charge pump supply of 3.3 V, optimal performance is for a typical charge pump output voltage between 0.5 and 2.8 volts.

Figure 1. Charge Pump Current for Vcp = 3.3 V



For a charge pump supply voltage of 5 volts or higher, optimal performance is typically for a charge pump output voltage between 0.5 and 4.5 volts.

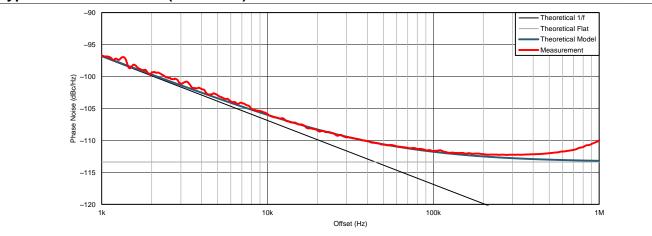
Figure 2. Charge Pump Current for Vcp = 5.5 V



Typical value of lowest power level as a function of frequency. Design to electrical specifications for input sensitivity, not typical performance graphs.

Figure 3. Fin Input Sensitivity

Typical Characteristics (continued)



This plot is for a phase detector of 100 MHz, 2 MHz loop bandwidth, and VCO at 9600 MHz. However, the plot shown is the divide by 2 port at 4800 MHz. The input was a 100 MHz Wenzel Oscillator. The model shows this phase noise has a figure of merit of -227 dBc/Hz and a normalized 1/f noise of -120.5 dBc/Hz. The charge pump supply was 5 V and the charge pump output voltage was 1.34 V.

Figure 4. LMX2492/92-Q1 Phase Noise for Fpd =100 MHz, Fvco = 9600 MHz/2

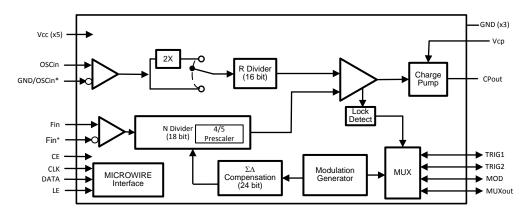


8 Detailed Description

8.1 Overview

The LMX2492/92-Q1 is a microwave PLL, consisting of a reference input and divider, high frequency input and divider, charge pump, ramp generator, and other digital logic. The Vcc power supply pins run at a nominal 3.3 volts, while the charge pump supply pin, Vcp, operates anywhere from Vcc to 5 volts. The device is designed to operate with an external loop filter and VCO. Modulation is achieved by manipulating the MASH engine.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 OSCin Input

The reference can be applied in several ways. If using a differential input, this should be terminated differentially with a 100 ohm resistance and AC coupled to the OSCin and GND/OSCin* terminals. If driving this single-ended, then the GND/OSCin* terminal may be grounded, although better performance is attained by connecting the GND/OSCin* terminal through a series resistance and capacitance to ground to match the OSCin terminal impedance.

8.3.2 OSCin Doubler

The OSCin doubler allows the input signal to the OSCin to be doubled in order to have higher phase detector frequencies. This works by clocking on both the rising and falling edges of the input signal, so it therefore requires a 50% input duty cycle.

8.3.3 R Divider

The R counter is 16 bits divides the OSCin signal from 1 to 65535. If DIFF_R = 0, then any value can be chosen in this range. If DIFF R=1, then the divide is restricted to 2,4,8, and 16, but allows for higher OSCin frequencies.

8.3.4 PLL N Divider

The 16 bit N divider divides the signal at the Fin terminal down to the phase detector frequency. It contains a 4/5 prescaler that creates minimum divide restrictions, but allows the N value to increment in values of one.

Modulator Order	Minimum N Divide
Integer Mode, 1st Order Modulator	16
2nd Order Modulator	17
3rd Order Modulator	19
4th Order Modulator	25

ZHCSCB6-MARCH 2014 www.ti.com.cn

8.3.5 Fractional Circuitry

The fractional circuitry controls the N divider with delta sigma modulation that supports a programmable first, second, third, and fourth order modulator. The fractional denominator is a fully programmable 24-bit denominator that can support any value from 1,2,..., 224, with the exception when the device is running one of the ramps, and in this case it is a fixed size of 2²⁴.

8.3.6 PLL Phase Detector and Charge Pump

The phase detector compares the outputs of the R and N dividers and generates a correction voltage corresponding to the phase error. This voltage is converted to a correction current by the charge pump. The phase detector frequency, f_{PD}, can be calculated as follows: f_{PD} = f_{OSCin} × OSC_2X / R.

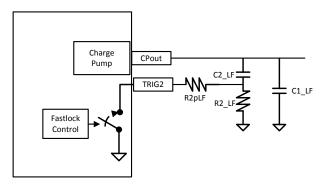
The charge pump supply voltage on this device, Vcp, can be either run at the Vcc voltage, or up to 5.25 volts in order to get higher tuning voltages to present to the VCO.

8.3.7 External Loop Filter

The loop filter is external to the device and is application specific. Texas Instruments website has details on this at www.ti.com.

8.3.8 Fastlock and Cycle Slip Reduction

The Fastlock[™] and Cycle Slip Reduction features can be used to improved lock time. When the frequency is changed, a timeout counter can be used to engage these features for a prescribed number of phase detector cycles. During this time that the timeout counter is counting down, the device can be used to pull a terminal from high impedance to ground switch in an extra resistor (R2pLF), change the charge pump current (FL_CPG), or change the phase detector frequency. TRIG2 is recommended for switching the resistor with a setting of TRIG2_MUX = Fastlock (2) and TRIG2_PIN = Inverted/Open Drain (5).



Parameter	Normal Operation	Fastlock Operation
Charge Pump Gain	CPG	FL_CPG
Device Pin (TRIG1, TRIG2, MOD, or MUXout)	High Impedance	Grounded

The resistor and the charge pump current are changed simultaneously so that the phase margin remains the same while the loop bandwidth is by a factor of K as shown in the following table:

Parameter	Symbol	Calculation		
Charge Pump Gain in Fastlock	FL_CPG	Typically use the highest value.		
Loop Bandwidth Multiplier	К	K=sqrt(FL_CPG/CPG)		
External Resistor	R2pLF	R2 / (K-1)		

ZHCSCB6-MARCH 2014 www.ti.com.cn

Cycle slip reduction is another method that can also be used to speed up lock time by reducing cycle slipping. Cycle slipping typically occurs when the phase detector frequency exceeds about 100x the loop bandwidth of the PLL. Cycle slip reduction works in a different way than fastlock. To use this, the phase detector frequency is decreased while the charge pump current is simultaneously increased by the same factor. Although the loop bandwidth is unchanged, the ratio of the phase detector frequency to the loop bandwidth is, and this is helpful for cases when the phase detector frequency is high. Because cycle slip reduction changes the phase detector rate. it also impacts other things that are based on the phase detector rate, such as the fastlock timeout-counter and ramping controls.

8.3.9 Lock Detect and Charge Pump Voltage Monitor

The LMX2492/92-Q1 offers two methods to determine if the PLL is in lock, charge pump voltage monitoring and digital lock detect. These features can be used individually or in conjunction to give a reliable indication of when the PLL is in lock. The output of this detection can be routed to the TRIG1, TRIG2, MOD, or MUXout terminals.

8.3.9.1 Charge Pump Voltage Monitor

The charge pump voltage monitor allows the user to set low (CMP_THR_LOW) and high (CMP_THR_HIGH) thresholds for a comparator that monitors the charge pump output voltage.

Vcp	Threshold	Suggested Level
22.7	CPM_THR_LOW = (Vthresh + 0.08) / 0.085	6 for 0.5V limit
3.3 V	CPM_THR_HIGH = (Vthresh - 0.96) / 0.044	42 for 2.8V limit
50.7	CPM_THR_LOW = (Vthresh + 0.056) / 0.137	4 for 0.5V limit
5.0 V	CPM_THR_HIGH = (Vthresh -1.23) / 0.071	46 for 4.5V limit

8.3.9.2 Digital Lock Detect

Digital lock detect works by comparing the phase error as presented to the phase detector. If the phase error plus the delay as specified by the PFD DLY bit is outside the tolerance as specified by DLD TOL, then this comparison would be considered to be an error, otherwise passing. The DLD_ERR_CNT specifies how may errors are necessary to cause the circuit to consider the PLL to be unlocked. The DLD PASS CNT specifies how many passing comparisons are necessary to cause the PLL to be considered to be locked and also resets the count for the errors. The DLD TOL value should be set to no more than half of a phase detector period plus the PFD DLY value. The DLD ERR CNT and DLD PASS CNT values can be decreased to make the circuit more sensitive. If the circuit is too sensitive, then chattering can occur and the DLD ERR CNT. DLD_PASS_CNT, or DLD_TOL values should be increased.

Note that if the OSCin signal goes away and there is no noise or self-oscillation at the OSCin pin, then it is possible for the digital lock detect to indicate a locked state when the PLL really is not in lock. If this is a concern. then digital lock detect can be combined with charge pump voltage monitor to detect this situation...

8.3.10 FSK/PSK Modulation

Two level FSK or PSK modulation can be created whenever a trigger event, as defined by the FSK TRIG field is detected. This trigger can be defined as a transition on a terminal (TRIG1, TRIG2, MOD, or MUXout) or done purely in software. The RAMP_PM_EN bit defines the modulation to be either FSK or PSK and the FSK_DEV register determines the amount of the deviation. Remember that the FSK_DEV[32:0] field is programmed as the 2's complement of the actual desired FSK DEV value. This modulation can be added to the modulation created from the ramping functions as well.

RAMP_PM_EN	RAMP_PM_EN Modulation Type				
0	2 Level FSK	Fpd x FSK_DEV / 2 ²⁴			
1	2 Level PSK	360° × FSK_DEV / 2 ²⁴			

www.ti.com.cn



8.3.11 Ramping Functions

The LMX2492/92-Q1 supports a broad and flexible class of FMCW modulation formed by up to 8 linear ramps. When the ramping function is running, the denominator is fixed to a forced value of $2^{2^4} = 16777216$. The waveform always starts at RAMP0 when the LSB of the PLL_N (R16) is written to. After it is set up, it will start at the initial frequency and have piecewise linear frequency modulation that deviates from this initial frequency as specified by the modulation. Each of the eight ramps can be individually programmed. Various settings are as follows

Ramp Characteristic	Programming Field Name	Description
Ramp Length	RAMPx_LEN RAMPx_DLY	The user programs the length of the ramp in phase detector cycles. If RAMPx_DLY=1, then each count of RAMPx_LEN is actually two phase detector cycles.
Ramp Slope	RAMPx_LEN RAMPx_DLY RAMPx_INC	The user does not directly program slope of the line, but rather this is done by defining how long the ramp is and how much the fractional numerator is increased per phase detector cycle. The value for RAMPx_INC is calculated by taking the total expected increase in the frequency, expressed in terms of how much the fractional numerator increases, and dividing it by RAMPx_LEN. The value programmed into RAMPx_INC is actually the two's complement of the desired mathematical value.
Trigger for Next Ramp	RAMPx_NEXT_TRIG	The event that triggers the next ramp can be defined to be the ramp finishing or can wait for a trigger as defined by TRIG A, TRIG B, or TRIG C.
Next Ramp	RAMPx_NEXT	This sets the ramp that follows. Waveforms are constructed by defining a chain ramp segments. To make the waveform repeat, make RAMPx_NEXT point to the first ramp in the pattern.
Ramp Fastlock	RAMPx_FL	This allows the ramp to use a different charge pump current or use Fastlock
Ramp Flags	RAMPx_FLAG	This allows the ramp to set a flag that can be routed to external terminals to trigger other devices.

8.3.11.1 Ramp Count

If it is desired that the ramping waveform keep repeating, then all that is needed is to make the RAMPx_NEXT of the final ramp equal to the first ramp. This will run until the RAMP_EN bit is set to zero. If this is not desired, then one can use the RAMP_COUNT to specify how may times the specified pattern is to repeat.

8.3.11.2 Ramp Comparators and Ramp Limits

The ramp comparators and ramp limits use programable thresholds to allow the device to detect whenever the modulated waveform frequency crosses a limit as set by the user. The difference between these is that comparators set a flag to alert the user while a ramp limits prevent the frequency from going beyond the prescribed threshold. In either case, these thresholds are expressed by programming the Extended_Fractional_Numerator.

Extended_Fractional_Numerator = Fractional_Numerator + (N-N*) > 2²⁴

Extended_Fractional_Numerator = Fractional_Numerator + $(N-N^*)$ x 2^{2^4} In the above, N is the PLL feedback value without ramping and N* is the instantaneous value during ramping. The actual value programmed is the 2's complement of Extended_Fractional_Numerator.

Туре	Programming Bit	Threshold
Doma Limita	RAMP_LIMIT_LOW	Lower Limit
Ramp Limits	RAMP_LIMIT_HIGH	Upper Limit
Ramp Comparators	RAMP_CMP0 RAMP_CMP1	For the ramp comparators, if the ramp is increasing and exceeds the value as specified by RAMP_CMPx, then the flag will go high, otherwise it is low. If the ramp is decreasing and goes below the value as specified by RAMP_CMPx, then the flag will go high, otherwise it will be low.

8.3.12 Power on Reset (POR)

The power on reset circuitry sets all the registers to a default state when the device is powered up. This same reset can be done by programming SWRST=1. In the programming section, the power on reset state is given for all the programmable fields.

ZHCSCB6-MARCH 2014 www.ti.com.cn

8.4 Device Functional Modes

The two primary ways to use the LMX2492/92-Q1 are to run it to generate a set of frequencies

8.4.1 Continuous Frequency Generator

In this mode, the LMX2492/92-Q1 generates a single frequency that only changes when the N divider is programmed to a new value. In this mode, the RAMP_EN bit is set to 0 and the ramping controls are not used. The fractional denominator can be programmed to any value from 1 to 16777216. In this kind of application, the PLL is tuned to different channels, but at each channel, the goal is to generate a stable fixed frequency.

8.4.1.1 Integer Mode Operation

In integer mode operation, the VCO frequency needs to be an integer multiple of the phase detector frequency. This can be the case when the output frequency or frequencies are nicely related to the input frequency. As a rule of thumb, if this an be done with a phase detector of as high as the lesser of 10 MHz or the OSCin frequency, then this makes sense. To operate the device in integer mode, disable the fractional circuitry by programming the fractional order (FRAC_ORDER), dithering (FRAC_DITH), and numerator (FRAC_NUM) to zero.

8.4.1.2 Fractional Mode Operation

In fractional mode, the output frequency does not need to be an integer multiple of the phase detector frequency. This makes sense when the channel spacing is more narrow or the input and output frequencies are not nicely related. There are several programmable controls for this such as the modulator order, fractional dithering, fractional numerator, and fractional denominator. There are many trade-offs with choosing these, but here are some guidelines

Parameter	Field Name	How to Choose
Fractional Numerator and Denominator	FRAC_NUM FRAC_DEN	The first step is to find the fractional denominator. To do this, find the frequency that divides the phase detector frequency by the channel spacing. For instance, if the output ranges from 5000 to 5050 in 5 MHz steps and the phase detector is 100 MHz, then the fractional denominator is 100 MHz/5 = 20. So for a an output of 5015 MHz, the N divider would be 50 + 3/20. In this case, the fractional numerator is 3 and the fractional denominator is 20. Sometimes when dithering is used, it makes sense to express this as a larger equivalent fraction. Note that if ramping is active, the fractional denominator is forced to 2^{24} .
Fractional Order	FRAC_ORDER	There are many trade-offs, but in general try either the 2nd or 3rd order modulator as starting points. The 3rd order modulator may give lower main spurs, but may generate others. Also if dithering is involved, it can generate phase noise.
Dithering	FRAC_DITH	Dithering can reduce some fractional spurs, but add noise. Consult application note AN-1879 for more details on this.

8.4.2 Modulated Waveform Generator

In this mode, the device can generate a broad class of frequency sweeping waveforms. The user can specify up to 8 linear segments in order to generate these waveforms. When the ramping function is running, the denominator is fixed to a forced value of $2^{24} = 16777216$

In addition to the ramping functions, there is also the capability to use a terminal to add phase or frequency modulation that can be done by itself or added on top of the waveforms created by the ramp generation functions.



8.5 Programming

8.5.1 Loading Registers

The device is programmed using several 24 bit registers. The first 16 bits of the register are the address, followed by the next 8 bits of data. The user has the option to pull the LE terminal high after this data, or keep sending data and it will apply this data to the next lower register. So instead of sending three registers of 24 bits each, one could send a single 40 bit register with the 16 bits of address and 24 bits of data. For that matter, the entire device could be programmed as a single register if desired.

8.6 Register Map

Registers are programmed in REVERSE order from highest to lowest. Registers NOT shown in this table or marked as reserved can be written as all 0's unless otherwise stated. The POR value is the power on reset value that is assigned when the device is powered up or the SWRST bit is asserted.

Table 1. Register Map

Reg	jister	D7	D6	D5	D4	D3	D2	D1	D0	POR
0	0	0	0	0	1	1	0	0	0	0x18
1	0x1		1	I	Rese	erved	I	1	•	0x00
2	0x2	0	0	0	0	0	SWRST	POWERD	OWN[1:0]	0x00
3-15	0x3 - 0xF			•	Rese	erved	•			-
16	0x10				PLL_I	N[7:0]				0x64
17	0x11				PLL_N	N[15:8]				0x00
18	0x12	0	FR	AC_ORDER[2:0]	FRAC_DI	THER[1:0]	PLL_N	I[17:16]	0x00
19	0x13				FRAC_N	IUM[7:0]				0x00
20	0x14				FRAC_N	UM[15:8]				0x00
21	0x15				FRAC_NI	JM[23:16]				0x00
22	0x16				FRAC_E	DEN[7:0]				0x00
23	0x17				FRAC_D	EN[15:8]				0x00
24	0x18				FRAC_DI	EN[23:16]				0x00
25	0x19				PLL_I	R[7:0]				0x04
26	0x1A				PLL_F	R[15:8]				0x00
27	0x1B	0	FL_CS	SR[1:0]	PFD_D	LY[1:0]	PLL_R_ DIFF	0	OSC_2X	0x08
28	0x1C	0	0	CPPOL			CPG[4:0]			0x00
29	0x1D	F	L_TOC[10:8	5]			FL_CPG[4:0]			0x00
30	0x1E	0	CPM_ FLAGL			CPM_THR	_LOW[5:0]			0x0a
31	0x1F	0	CPM_ FLAGH			CPM_THR	_HIGH[5:0]			0x32
32	0x20				FL_TC	C[7:0]				0x00
33	0x21				DLD_PASS	S_CNT[7:0]				0x0f
34	0x22		DLD_TOL[2:0)]		DLD	_ERR_CNTF	R[4:0]		0x00
35	0x23	MOD_ MUX[5]	1	MUXout _MUX[5]	TRIG2 _MUX[5]	TRIG1 _MUX[5]	0	0	1	0x41
36	0x24		TF	RIG1_MUX[4	:0]		Т	RIG1_PIN[2:	0]	0x08
37	0x25		TF	RIG2_MUX[4	:0]		Т	RIG2_PIN[2:	0]	0x10
38	0x26		N	1OD_MUX[4:	0]		N	MOD_PIN[2:0	0]	0x18
39	0x27		MU	JXout_MUX[4	1:0]		М	UXout_PIN[2	::0]	0x38
40-57	0x28-0x39				Rese	erved				-

www.ti.com.cn

Register Map (continued)

Table 1. Register Map (continued)

Re	gister	D7 I	D6	D5	D4	D3	D2	D1	D0	POR
58	0x3A	RA	AMP_TR	RIG_A[3:0]	RAMP_ PM_EN	RAMP_ CLK	RAMP_EN	0x00		
59	0x3B	RA	AMP_TR	RIG_C[3:0]			RAMP_TI	RIG_B[3:0]		0x00
60	0x3C				RAMP_C	MP0[7:0]				0x00
61	0x3D				RAMP_C	MP0[15:8]				0x00
62	0x3E				RAMP_CN	/IP0[23:16]				0x00
63	0x3F				RAMP_CN	/IP0[31:24]				0x00
64	0x40				RAMP_CM	P0_EN[7:0]				0x00
65	0x41				RAMP_C	MP1[7:0]				0x00
66	0x42				RAMP_C	MP1[15:8]				0x00
67	0x43				RAMP_CN	/IP1[23:16]				0x00
68	0x44				RAMP_CN	/IP1[31:24]				0x00
69	0x45				RAMP_CM	P1_EN[7:0]				0x00
70	0x46	0	FSK_TRIG[1:0] R.			RAMP_ LIML[32]	FSK_ DEV[32]	RAMP_ CMP1[32]	RAMP_ CMP0[32]	0x08
71	0x47				FSK_D	EV[7:0]				0x00
72	0x48				FSK_DI	EV[15:8]				0x00
73	0x49				FSK_DE	V[23:16]				0x00
74	0x4A				FSK_DE	V[31:24]				0x00
75	0x4B				RAMP_LIMI	T_LOW[7:0]				0x00
76	0x4C				RAMP_LIMI	Γ_LOW[15:8]				0x00
77	0x4D				RAMP_LIMIT	_LOW[23:16]			0x00
78	0x4E				RAMP_LIMIT	_LOW[31:24]			0x00
79	0x4F				RAMP_LIMI	T_HIGH[7:0]				0xff
80	0x50				RAMP_LIMIT	Γ_HIGH[15:8]				0xff
81	0x51	RAMP_LIMIT_HIGH[23:16]								0xff
82	0x52		RAMP_LIMIT_HIGH[31:24]							
83	0x53		RAMP_COUNT[7:0]							
84	0x54	RAMP_TRIG_IN	AMP_TRIG_INC[1:0] RAMP_ AUTO RAMP_COUNT[12:8]							
85	0x55		<u></u>		Reserved					

www.ti.com.cn

Register Map (continued)

Table 1. Register Map (continued)

Reg	gister	D7	D6	D5	D4	D3	B D2 D1 D0			POR	
86	0x56				RAMP0_INC[7:0]						
87	0x57		RAMP0_INC[15:8]								
88	0x58				RAMP0_	NC[23:16]				0x00	
89	0x59	RAMP0_ DLY	RAMP0_ FL			RAMP0_I	NC[29:24]			0x00	
90	0x5A				RAMP0_	_LEN[7:0]				0x00	
91	0x5B				RAMP0_	LEN[15:8]				0x00	
92	0x5C	RA	MP0_NEXT[2	2:0]	RAM NEXT_1	ИР0_ TRIG[1:0]	RAMP0_ RST	RAMP0_I	FLAG[1:0]	0x00	
93	0x5D				RAMP1	_INC[7:0]				0x00	
94	0x5E				RAMP1_	INC[15:8]				0x00	
95	0x5F				RAMP1_	NC[23:16]				0x00	
96	0x60	RAMP1_ DLY	RAMP1_ FL			RAMP1_I	NC[29:24]			0x00	
97	0x61				RAMP1_	_LEN[7:0]				0x00	
98	0x62				RAMP1_	LEN[15:8]				0x00	
99	0x63	RA	MP1_NEXT[2	EXT[2:0] RAMP1_ RAMP1_ RAMP1_FLAG[1:0]				0x00			
100	0x64				RAMP2	_INC[7:0]	•	•		0x00	
101	0x65				RAMP2_	INC[15:8]				0x00	
102	0x66				RAMP2_	NC[23:16]				0x00	
103	0x67	RAMP2 DLY	RAMP2_ FL			RAMP2_I	NC[29:24]			0x00	
104	0x68		I	I	RAMP2_	_LEN[7:0]				0x00	
105	0x69				RAMP2_	LEN[15:8]				0x00	
106	0x6A	RA	MP2_NEXT[2	2:0]		//P2_ TRIG[1:0]	RAMP2_ RST	RAMP2_I	FLAG[1:0]	0x00	
107	0x6B				RAMP3	_INC[7:0]	"	I.		0x00	
108	0x6C				RAMP3_	INC[15:8]				0x00	
109	0x6D				RAMP3_	NC[23:16]				0x00	
110	0x6E	RAMP3_ DLY	RAMP3_ FL	RAMP3_INC[29:24]					0x00		
111	0x6F		ı	ı	RAMP3_	_LEN[7:0]				0x00	
112	0x70				RAMP3_	LEN[15:8]				0x00	
113	0x71	RA	MP3_NEXT[2	2:0]		//P3_ TRIG[1:0]	RAMP3_ RST	RAMP3_I	FLAG[1:0]	0x00	

ZHCSCB6-MARCH 2014 www.ti.com.cn

Register Map (continued)

Table 1. Register Map (continued)

Regi	ster	D7	D6	D5	D4	D3	D2	D1	D0	POR
114	0x72				RAMP4	_INC[7:0]				0x00
115	0x73		RAMP4_INC[15:8]							
116	0x74				RAMP4_	NC[23:16]				0x00
117	0x75	RAMP4_ DLY	RAMP4_ FL			RAMP4_	INC[29:24]			0x00
118	0x76				RAMP4_	_LEN[7:0]				0x00
119	0x77				RAMP4_	LEN[15:8]				0x00
120	0x78	RA	MP4_NEXT[2:0]		/IP4_ TRIG[1:0]	RAMP4_ RST	RAMP4_	FLAG[1:0]	0x00
121	0x79				RAMP5	_INC[7:0]				0x00
122	0x7A				RAMP5_	INC[15:8]				0x00
123	0x7B				RAMP5_	NC[23:16]				0x00
124	0x7C	RAMP5_ DLY	RAMP5_ FL			RAMP5_	INC[29:24]			0x00
125	0x7D		I.		RAMP5_	_LEN[7:0]				0x00
126	0x7E				RAMP5_	LEN[15:8]				0x00
127	0x7F	RA	RAMP5_NEXT[2:0]						FLAG[1:0]	0x00
128	0x80				RAMP6	_INC[7:0]				0x00
129	0x81				RAMP6_	INC[15:8]				0x00
130	0x82				RAMP6_	NC[23:16]				0x00
131	0x83	RAMP6_ DLY	RAMP6_ FL			RAMP6_	INC[29:24]			0x00
132	0x84				RAMP6_	_LEN[7:0]				0x00
133	0x85				RAMP6_	LEN[15:8]				0x00
134	0x86	RA	MP6_NEXT[2:0]	RAN NEXT_1	/IP6_ TRIG[1:0]	RAMP6_ RST	RAMP6_	FLAG[1:0]	0x00
135	0x87				RAMP7	_INC[7:0]				0x00
136	0x88				RAMP7_	INC[15:8]				0x00
137	0x89				RAMP7_	NC[23:16]				0x00
138	0x8A	RAMP7_ DLY	RAMP7_ FL			RAMP7_	INC[29:24]			0x00
139	0x8B		ı	ı	RAMP7_	_LEN[7:0]				0x00
140	0x8C				RAMP7_	LEN[15:8]				0x00
141	0x8D	RA	MP7_NEXT[2:0]	DAMD7 DAMD7					0x00
142-32767	0x8E- 0x7fff				Res	erved				0x00



8.7 Register Field Descriptions

The following sections go through all the programmable fields and their states. Additional information is also available in the applications and feature descriptions sections as well. The POR column is the power on reset state that this field assumes if not programmed.

8.7.1 POWERDOWN and Reset Fields

Table 2. POWERDOWN and Reset Fields

Field	Location	POR	Description and States					
				Value	POWERDOWN State			
			POWERDOWN Control	0	POWERDOWN, ignore CE			
POWERDOWN	R2[1:0]	0		1	Power Up, ignore CE			
[1:0]				2	Power State Defined by CE terminal state			
				3	Reserved			
	R2[2]	0			Value	Reset State		
SWRST			Software Reset. Setting this bit sets all registers to their POR default values.	0	Normal Operation			
			registers to their r Ork default values.	1	Register Reset			

www.ti.com.cn

8.7.2 Dividers and Fractional Controls

Table 3. Dividers and Fractional Controls

Field	Location	POR	Description and States		
PLL_N [17:0]	R18[1] to R16[0]	16	Feedback N counter Divide value. Minimum the register R16 begins any ramp execution		
				Value	Dither
				0	Weak
FRAC_ DITHER [1:0]	R18[3:2]	0	Dither used by the fractional modulator	1	Medium
[1.0]				2	Strong
				3	Disabled
				Value	Modulator Order
				0	Integer Mode
				1	1st Order Modulator
FRAC_ ORDER [2:0]	R18[6:4]	0	Fractional Modulator order	2	2nd Order Modulator
[2.0]				3	3rd Order Modulator
				4	4th Order Modulator
				5-7	Reserved
FRAC_NUM [23:0]	R21[7] to R19[0]	0	Fractional Numerator. This value should denominator.	be less that	an or equal to the fractional
FRAC_DEN [23:0]	R24[7] to R22[0]	0	Fractional Denominator. If the RAMP_EN=1, this field is ignored and the denominator is fixed to 2^{24} .		
PLL_R [15:0]	R26[7] to R25[0]	1	Reference Divider value. Selecting 1 will bypass counter.		
	R27[0]	0	Enables the Doubler before the Reference divider	Value	Doubler
OSC_2X				0	Disabled
			dividei	1	Enabled
			Enables the Differential R counter. This allows for higher OSCin frequencies, but restricts PLL_R to divides of 2,4,8 or	Value	R Divider
PLL_R _DIFF	R27[2]	0		0	Single-Ended
			16.	1	Differential
				Value	Pulse Width
			Sets the charge pump minimum pulse	0	Reserved
PFD_DLY [1:0]	R27[4:3]	1	width. This could potentially be a trade-off between fractional spurs and phase noise.	1	860 ps
[1.0]			Setting 1 is recommended for general use.	2	1200 ps
				3	1500 ps
				Value	Charge Pump State
				0	Tri-State
CPG	Doct 4 cl	_	Oleanna annia	1	100 uA
[4:0]	R28[4:0]	0	Charge pump gain	2	200 uA
				31	3100 uA
			Charge Pump Polarity	Value	Charge Pump Polarity
CPPOL	R28[5]	0	Charge Pump Polarity Positive is for a positive slope VCO	0	Negative
			characteristic, negative otherwise.	1	Positive



8.7.2.1 Speed Up Controls (Cycle Slip Reduction and Fastlock)

Table 4. FastLock and Cycle Slip Reduction

Field	Location	POR	Description and States			
			Cycle Slip Reduction (CSR) reduces the	Value	CSR Value	
			phase detector frequency by multiplying both the R and N counters by the CSR	0	Disabled	
			value while either the FastLock Timer is	1	x 2	
FL_ CSR [1:0]	R27[6:5]	0	counting or the RAMPx_FL=1 and the part	2	x 4.	
[1.0]	[1:0]		is ramping. Care must be taken that the R and N divides remain inside the range of the counters. Cycle slip reduction is generally not recommended during ramping.	3	Reserved	
				Value	Fastlock Charge Pump Gain	
	FL_CPG P2014-01	0] 0	Charge pump gain only when Fast Lock Timer is counting down or a ramp is running with RAMPx_FL=1	0	Tri-State	
FL_ CPG				1	100 uA	
[4:0]	R29[4:0]			2	200 uA	
				31	3100 uA	
			Fast Lock Timer. This counter starts	Value	Fastlock Timer Value	
			counting when the user writes the PLL_N(Register R16). During this time the	0	Disabled	
FL_ TOC	R29[7:5]		FL_CPG gain is sent to the charge pump,	1	1 x 32 = 32	
[10:0]	and R32[7:0]	0	and the FL_CSR shifts the R and N counters if enabled. When the counter			
			terminates, the normal CPG is presented and the CSR undo's the shifts to give a normal PFD frequency.	2047	2047 x 32 = 65504	

www.ti.com.cn ZHCSCB6-MARCH 2014

8.8 Lock Detect and Charge Pump Monitoring

Table 5. Lock Detect and Charge Pump Monitor

Field	Location	POR	Description and States		
				Value	Threshold
CPM_THR _LOW	R30[5:0]	0x0A	Charge pump voltage low threshold value. When the charge pump voltage is below	0	Lowest
[5:0]	K30[3.0]	UXUA	this threshold, the LD goes low.		
			·	63	Highest
				Value	Flag Indication
CPM_FLAGL	R30[6]	-	This is a read only bit. Low indicates the charge pump voltage is	0	Charge pump is below CPM_THR_LOW threshold
			below the minimum threshold.	1	Charge pump is above CPM_THR_LOW threshold
				Value	Threshold
CPM_THR _HIGH	D04[5.0]	020	Charge pump voltage high threshold value.	0	Lowest
[5:0]	R31[5:0]	0x32	When the charge pump voltage is above this threshold, the LD goes low.		
			, 0	63	Highest
			This is a read only bit. Charge pump voltage high comparator reading. High indicates the charge pump voltage is above the maximum threshold.	Value	Threshold
CPM_FLAGH	R31[6]	-		0	Charge pump is below CPM_THR_HIGH threshold
				1	Charge pump is above CPM_THR_HIGH threshold
DLD_ PASS_CNT [7:0]	R33[7:0]	0xff	Digital Lock Detect Filter amount. There must be at least DLD_PASS_CNT good ed and less than DLD_ERR edges before the DLD is considered in lock. Making this num smaller will speed the detection of lock, but also will allow a higher chance of DLD chat		
DLD_ ERR_CNT [4:0]	R34[4:0]	0	Digital Lock Detect error count. This is th DLD_TOL that are allowed before DLD is recommended value is 4.		
				Value	Window and Fpd Frequency
				0	1 ns (Fpd > 130 MHz)
			Digital Lock detect edge window. If both N and R edges are within this window, it is considered a "good" edge. Edges that are	1	1.7 ns (80 MHz , Fpd ≤ 130 MHz)
DLD _TOL	D24[7:E]	0	farther apart in time are considered "error"	2	3 ns (60 MHz , Fpd ≤ 80 MHz)
[2:0]	R34[7:5]	U	edges. Window choice depends on phase	3	6 ns (45 MHz , Fpd ≤ 60 MHz)
			detector frequency, charge pump minimum pulse width, fractional modulator order and the users desired margin.	4	10 ns (30 MHz < Fpd ≤ 45 MHz)
				5	18 ns (Fpd ≤ 30 MHz)
				6 and 7	Reserved



8.9 TRIG1,TRIG2,MOD, and MUXout Pins

Table 6. TRIG1, TRIG2, MOD, and MUXout Terminal States

Field	Location	POR	Description and States		
				Value	Pin Drive State
TRIG1 _PIN	R36[2:0]	0		0	TRISTATE (default)
[2:0]	K30[2.0]	0		1	Open Drain Output
			This is the terminal drive state for the TRIG1, TRIG2, MOD, and MUXout Pins	2	Pullup / Pulldown Output
TRIG2 _PIN [2:0]	R37[2:0]	0		3	Reserved
MODPIN [2:0]	R38[2:0]	0		4	GND
				5	Inverted Open Drain Output
MUXoutPIN [2:0]	R39[2:0]	0		6	Inverted Pullup / Pulldown Output
				7	Input



Table 7. TRIG1, TRIG2, MOD, and MUXout Selections

Field	Location	POR	Description	and States	
				Value	MUX State
				0	GND
				1	Input TRIG1
				2	Input TRIG2
				3	Input MOD
				4	Output TRIG1 after synchronizer
				5	Output TRIG2 after synchronizer
				6	Output MOD after synchronizer
				7	Output Read back
				8	Output CMP0
				9	Output CMP1
				10	Output LD (DLD good AND CPM good)
				11	Output DLD
				12	Output CPMON good
				13	Output CPMON too High
				14	Output CPMON too low
TRIG1_MUX	R36[7:3],		These fields control what signal is muxed to or from the TRIG1,TRIG2, MOD, and	15	Output RAMP LIMIT EXCEEDED
[5:0] TRIG2_MUX	R37.3 R36[7:3],	1	MUXout pins. Some of the abbreviations used are:	16	Output R Divide/2
[5:0]	R35.3	2	COMP0, COMP1: Comparators 0 and 1	17	Output R Divide/4
MOD_MUX [5:0]	R37[7:3], R35.4	3 7	LD, DLD: Lock Detect, Digital Lock Detect CPM: Charge Pump Monitor	18	Output N Divide/2
MUXout_MUX	R38[7:3],		CPG: Charge Pump Gain	19	Output N Divide/4
[5:0]	R35.7		CPUP: Charge Pump Up Pulse CPDN: Charge Pump Down Pulse	20	Reserved
			or zim omange i amp zemi i anec	21	Reserved
				22	Output CMP0RAMP
				23	Output CMP1RAMP
				24	Reserved
				25	Reserved
				26	Reserved
				27	Reserved
				28	Output Faslock
				29	Output CPG from RAMP
				30	Output Flag0 from RAMP
				31	Output Flag1 from RAMP
				32	Output TRIGA
				33	Output TRIGB
				34	Output TRIGC
				35	Output R Divide
				36	Output CPUP
				37	Output CPDN
				38	Output RAMP_CNT Finished
				39 to 63	Reserved



8.10 Ramping Functions

Table 8. Ramping Functions

Field	Location	POR	Description and States						
			Enables the RAMP functions. When this bit	Value	Ramp				
DAMD EN	DEGIOI	0	is set, the Fractional Denominator is fixed to 2 ²⁴ . RAMP execution begins at RAMP0	0	Disabled				
RAMP_EN	R58[0]	0	upon the PLL_N[7:0] write. The Ramp should be set up before RAMP_EN is set.	1	Enabled				
			RAMP clock input source. The ramp can	Value	Source				
RAMP_CLK	R58[1]	0	be clocked by either the phase detector clock or the MOD terminal based on this	0	Phase Detector				
			selection.	1	MOD Terminal				
				Value	Modulation Type				
RAMP_PM_EN	R58[2]	0	Phase modulation enable.	0	Frequency Modulation				
				1	Phase Modulation				
				Value	Source				
				0	Never Triggers (default)				
				1	TRIG1 terminal rising edge				
				2	TRIG2 terminal rising edge				
				3	MOD terminal rising edge				
				4	DLD Rising Edge				
RAMP_TRIGA				5	CMP0 detected (level)				
[3:0]	R58[7:4]			6	RAMPx_CPG Rising edge				
RAMP_TRIGB [3:0]	R59[3:0]	0	Trigger A,B, and C Sources	7	RAMPx_FLAG0 Rising edge				
RAMP_TRIGC	R59[7:4]			8	Always Triggered (level)				
[3:0]				9	TRIG1 terminal falling edge				
				10	TRIG2 terminal falling edge				
				11	MOD terminal falling edge				
				12	DLD Falling Edge				
					i			13	CMP1 detected (level)
				14	RAMPx_CPG Falling edge				
				15	RAMPx_FLAG0 Falling edge				
RAMP_CMP0 [32:0]	R70[0], R63[7] to R60[0]	0	Twos compliment of Ramp Comparator 0 va R70.	alue. Be aware	e of that the MSB is in Register				
RAMP_CMP0_EN [7:0]	R64[7:0]	0	Comparator 0 is active during each RAMP c is active in and 0 for ramps it should be ignororresponds to R64[7]						
RAMP_CMP1 [32:0]	R70[1], R68[7] to R65[0]	0	Twos compliment of Ramp Comparator 1 va R70.	alue. Be aware	e of that the MSB is in Register				
RAMP_CMP1_EN [7:0]	R69[7:0]	0	Comparator 1 is active during each RAMP corresponding to the bit. Place a 1 for ramps is active in and 0 for ramps it should be ignored. RAMP0 corresponds to R64[0], RAMP corresponds to R64[7].						
				Value	Trigger				
	D=0		Deviation trigger source. When this trigger	0	Always Triggered				
FSK_TRIG [1:0]			source specified is active, the FSK_DEV value is applied.	1	Trigger A				
[]	0[0]			2	Trigger B				
				3	Trigger C				
FSK_DEV [32:0]	R70[2], R74[7] to R71[0]	0	Twos compliment of the deviation value for frequency modulation and phase modulation. This value should be written with 0 when not used. Be aware that the MSB is in Register R70.						

www.ti.com.cn

Ramping Functions (continued)

Table 8. Ramping Functions (continued)

Field	Location	POR	Description and States					
RAMP_LIMIT_LOW [32:0]	R70[3], R78[7] to 75[0]	0x000 00000	Twos compliment of the ramp lower limit that the ramp can not go below . The ramp limit occurs before any deviation values are included. Care must be taken if the deviation is used and the ramp limit must be set appropriately. Be aware that the MSB is in Register R70.					
RAMP_LIMIT_HIGH [32:0]	R70[4], R82[7] to 79.0[0]	0xfffffff f	Twos compliment of the ramp higher limit that the ramp can not go above. The ramp limit occurs before any deviation values are included. Care must be taken if the deviation is used and the ramp limit must be set appropriately. Be aware that the MSB is in Register R70.					
RAMP_COUNT [12:0]	R84[4] to R83[0]	0	Number of RAMPs that will be executed before a trigger or ramp enable is brought down. Load zero if this feature is not used. Counter is automatically reset when RAMP_EN goes from 0 to 1.					
		0		Value	Ramp			
RAMP_AUTO	R84[5]		Automatically clear RAMP_EN when	0	RAMP_EN unaffected by ramp counter (default)			
10.101	No -[o]	Ü	RAMP Count hits terminal count.	1	RAMP_EN automatically brought low when ramp counter terminal counts			
				Value	Source			
RAMP_TRIG_INC	R84[7:6]		Increment Trigger source for RAMP	0	Increments occur on each ramp transition			
[1:0]		0	O Counter. To disable ramp counter, load a count value of 0.	1	Increment occurs on trigA			
				2	Increment occurs on trigB			
				3	Increment occurs on trigC			



8.11 Individual Ramp Controls

These bits apply for all eight ramps. For the field names, x can be 0,1,2,3,4,5,6, or 7.

Table 9. Individual Ramp Controls

Field	Location	POR	Description and States						
RAMPx _INC[29:0]	Varies	0	Signed ramp increme	Signed ramp increment.					
				Value	CPG				
RAMPx _FL	Varies	0	This enables fastlock and cycle slip reduction for ramp x.	0	Disabled				
				1	Enabled				
				Value	Clocks				
RAMPx _DLY	Varies	0	During this ramp, each increment takes 2 PFD cycles per LEN clock instead of the normal 1 PFD cycle. Slows the	0	1 PFD clock per RAMP tick.(default)				
_521			ramp by a factor of 2.	1	2 PFD clocks per RAMP tick.				
RAMPx _LEN	Varies	0	Number of PFD clocks (if DLY is 0) to continue to increment RAMP. 1=>1 cycle, 2=>2 etc. Maximum of 65536 cycles.						
			General purpose FLAGS sent out of RAMP.	Value	Flag				
	RAMPx _FLAG[1:0] Varies 0			0	Both FLAG1 and FLAG0 are zero. (default)				
		0		1	FLAG0 is set, FLAG1 is clear				
_1 2/(0[1:0]				2	FLAG0 is clear, FLAG1 is set				
				3	Both FLAG0 and FLAG1 are set.				
			Forces a clear of the ramp accumulator. This is used to	Value	Reset				
RAMP0 _RST	Varies	0	erase any accumulator creep that can occur depending on how the ramps are defined. Should be done at the start of a	0	Disabled				
			ramp pattern.	1	Enabled				
				Value	Operation				
RAMPx_			Determines what event is necessary to cause the state	0	RAMPx_LEN				
NEXT _TRIG	Varies	0	machine to go to the next ramp. It can be set to when the RAMPx_LEN counter reaches zero or one of the events for	1	TRIG_A				
[1:0]			Triggers A,B, or C.	2	TRIG_B				
				3	TRIG_C				
RAMP0 _NEXT[2:0]	Varies	0	The next RAMP to execute when the length counter times out						



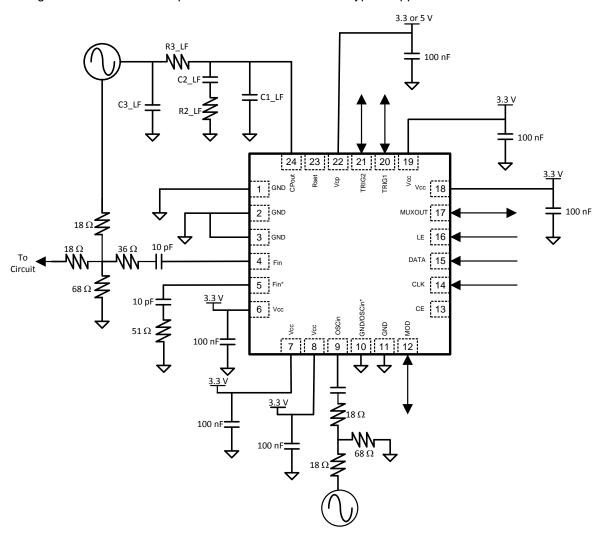
9 Applications and Implementation

9.1 Application Information

The LMX2492/92-Q1 can be used in a broad class of applications such as generating a single frequency for a high frequency clock, generating a tunable range of frequencies, or generating swept waveforms that can be used in applications such as radar.

9.2 Typical Applications

The following schematic is an example of hat could be used in a typical application.



9.2.1 Design Requirements

For these examples, it will be assumed that there is a 100 MHz input signal and the output frequency is between 9400 and 9800 MHz with various modulated waveforms.

Parameter	Symbol	Value	Comments
Input Frequency	OSCin	100 MHz	
Phase Detector Frequency	Fpd	100 MHz	There are many possibilities, but this choice gives good performance and saves a little current (as shown in the electrical specifications).



www.ti.com.cn

Typical Applications (continued)

Parameter	Symbol	Value	Comments
		9400 - 9800 MHz (Simple Chirp)	
VCO Frequency	Fyco	9400 - 9800 (Flattened Ramp)	In the different examples, the VCO frequency is actually changing. However, the same loop filter
Voc Frequency	1 100	9500 - 9625 MHz (Complex Triggered Ramp	design can be used for all three.
VCO Gain	Kvco	200 MHz/V	This parameter has nothing to do with the LMX2492/92-Q1, but is rather set by the external VCO choice.

9.2.2 Detailed Design Procedure

The first step is to calculate the reference divider (PLL_R) and feedback divider (PLL_N) values as shown in the table that follows.

Parameter	Symbol and Calculations	Value	Comments
Average VCO Frequency	$Fvco_{Avg} = (Fvco_{Max} + Fvco_{Min})/2$	9600 MHz	To design a loop filter, one designs for a fixed VCO value, although it is understood that the VCO will tune around. This typical value is usually chosen as the average VCO frequency.
VCO Gain	Kvco	200 MHz/V	This parameter has nothing to do with the LMX2492/92-Q1, but is rather set by the external VCO choice. In this case, it was the RFMD1843 VCO.
PLL Loop Bandwidth	BW	380 kHz	This bandwidth is very wide to allow the VCO frequency to be modulated.
Charge Pump Gain	CPG	3.1 mA	Using the larger gain allows a wider loop bandwidth and gives good phase performance.
R Divider	PLL_R = OSCin / Fpd	1	This value is calculated from previous values.
N Divider	PLL_N = Fvco / Fpd	96	This value is calculated from previous values.
	C1_LF	68 pF	
Loop Filter Components	C2_LF	3.9 nF	
	C3_LF	150 pF	These were calculated by TI design tools.
Componento	R2_LF	390 ohm	
	R3_LF	390 ohm	

Once a loop filter bandwidth is chosen, the external loop filter components of C1_LF, C2_LF, C3_LF, R2_LF, and R3_LF can be calculated with a tool such as the Clock Architect tool available at www.ti.com. It is also highly recommended to look at the EVM instructions. The CodeLoader software is an excellent starting point and example to see how to program this device.

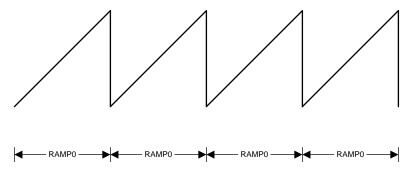


ZHCSCB6-MARCH 2014 www.ti.com.cn

9.2.3 Application Performance Plot - Sawtooth Waveform Example

Using the above design, it can be programmed to generate a sawtooth waveform with the following paramters.

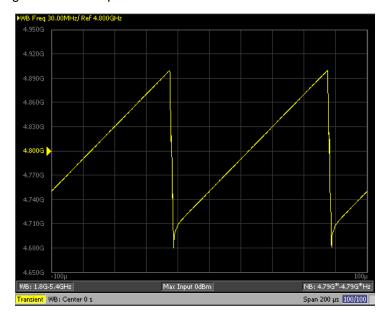
Parameter	Symbol	Value	
Ramp Duration	ΔΤ	100 uS	
VCO Frequency	Fvco	9400 - 9800 MHz	
Range	ΔF	9400 - 9800 MHz = 400 MHz Change	



Because we want the ramp length to be 100 us, this works out to 10,000 phase detector cycles which means that RAMP0_LEN=10000. To change 400 MHz, we know that each one of the 10000 steps is 40 kHz. Given the fractional denominator is $2^{24} = 16777216$ and the phase detector frequency is 100 MHz, this implies that the fractional numerator at the end of the ramp will be 6711. However, since this 6711 number is not exact (closer to 6718.8864), the ramp will creep if we do not reset it. Therefore, we set reset the ramp. After the ramp finishes, we want to start with the same ramp, so RAMP0 NEXT is RAMP0. The results of this analysis are in the table below:

RAMP	RAMP0_LEN	RAMP0_INC	RAMP0_NEXT	RAMP0_RST
RAMP0	$\Delta T \times Fpd = 100 \text{ us } / 100 \text{ MHz}$ = 10000	(ΔF / Fpd) /RAMP0_LEN × 2 ²⁴ = (400/100)/10000 ×16777216 = 6711	0	1

The actual measured waveform for this is shown in the following figure. Note that the frequency that was actually measured was from the divide by two output of the VCO and therefore the measured frequency was half of the actual frequency presented to the PLL. This ramping waveform does show some undershoot as the frequency rapidly returns from 9800 MHz (4900 MHz on the plot) to 9400 MHz (4700 MHz on the plot). This undershoot can be mitigated by adding additional ramps.

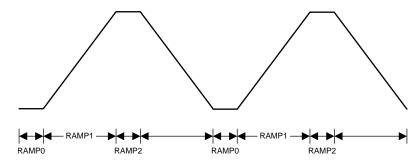




9.2.4 Application Performance Plot - Flat Top Triangle Waveform

Now consider pattern as shown below. The ramp is sometimes used because it can better account for Doppler Shift. The purpose for making the top and bottom portions flat is to help reduce the impact of the PLL overshooting and undershooting in order to make the sloped ramped portions more linear.

Parameter	Symbol	Value				
	ΔΤ0	10 uS				
Down Duration	ΔΤ1	90 uS				
Ramp Duration	ΔΤ2	10 uS				
	ΔΤ3	90 uS				
	ΔF0	0				
Danas	ΔF1	400 MHz				
Range	ΔF2	0				
	ΔF3	-400 MHz				



RAMP	RAMPx_LEN	RAMPx_INC	RAMPx_NEXT	RAMPx_RST
RAMP0	10 us/ 100 MHz =1000	0	1	1
RAMP1	90 us / 100 MHz =9000	(ΔF / Fpd) /RAMP1_LEN × 2 ²⁴ = (400/100)/9000 ×16777216 = 7457	2	0
RAMP2	10 us/ 100 MHz =1000	0	3	0
RAMP3	90 us / 100 MHz =9000	$(\Delta F / Fpd) / RAMP1_LEN \times 2^{24}$ = (-400/100)/9000 x16777216 = -7457 Program in 2's complement of -7457 = 2^{30} -7457 = 1073734367	0	0

NB: 4.79G*-4.79G*Hz

Span 500 µs 100/100



overshoot and undersoot in the frequency.

4.740G

4.710G

4,650G -250

Transient WB: Center 0 s

www.ti.com.cn

The actual measured waveform for this is shown in the following figure. Note that the frequency that was actually measured was from the divide by two output of the VCO and therefore the measured frequency was half of the actual frequency presented to the PLL. The flattened top and bottom of this triangle wave help mitigate the

Freq 30.00MHz/ Ref 4.800GHz

4.950G

1: -223 µs 4.699997562 GHz
2: -133 µs 4.89894432 GHz
3: -123 µs 4.90000183 GHz
4.920G

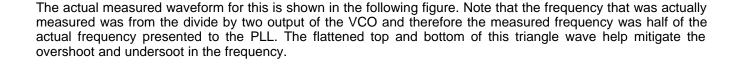
4.890G

4.890G

4.800G

4.800G

4.770G



Max Input 0dBm



9.2.5 Applications Performance Plot -- Complex Triggered Ramp

In this example, the modulation is not started until a trigger pulse from the MOD terminal goes high. Assume a phase detector frequency of 100 MHz and we RAMP1 to be 60 us and ramps 2,3,and 4 to be 12 us each. We set the next trigger for RAMP0 to be trigger A and define trigger A to be the MOD terminal. Then we configure as follows:

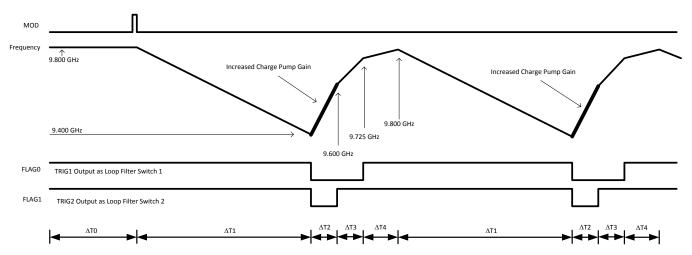


Figure 5. Complex Triggered Ramp Example

RAMP	RAMPx _LEN	RAMPx_ INC	RAMPx_FL	RAMPx _NEXT	RAMPx_FLAG	RAMPx_ NEXT_TRIG	RAMPx_RS T
RAMP0	1	0	0	1	FLAG0 and FLAG1	TRIG A	1
RAMP1	6000	1073730639	0	2	FLAG0 and FLAG1	TOC Timeout	1
RAMP2	1200	27963	1	3	Disabled	TOC Timeout	0
RAMP3	1200	17476	0	4	FLAG1	TOC Timeout	0
RAMP4	1200	10486	0	1	FLAG0 and FLAG1	TOC Timeout	0



ZHCSCB6-MARCH 2014 www.ti.com.cn

The actual measured waveform for this is shown in the following figure. Note that the frequency that was actually measured was from the divide by two output of the VCO and therefore the measured frequency was half of the actual frequency presented to the PLL. The flattened top and bottom of this triangle wave help mitigate the overshoot and undersoot in the frequency.

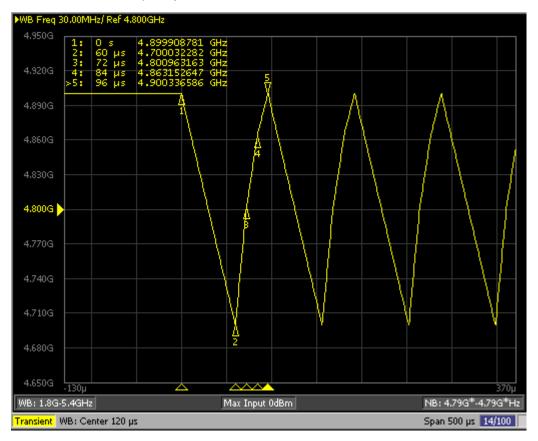


Figure 6. Actual Measurement for Complex Triggered Ramp

10 Power Supply Recommendations

For power supplies, it is recommended to place 100 nF close to each of the power supply pins. If fractional spurs are a large concern, using a ferrite bead to each of these power supply pins can reduce spurs to a small degree.

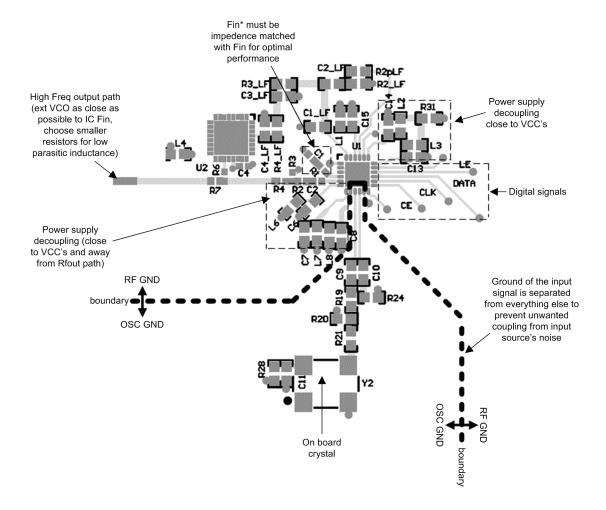


11 Layout

11.1 Layout Guidelines

For layout examples, the EVM instructions are the most comprehensive document. In general, the layout guidelines are similar to most other PLL devices. For the high frequency Fin pin, it is recommended to use 0402 components and match the trace width to these pad sizes. Also the same needs to be done on the Fin* pin. If layout is easier to route the signal to Fin* instead of Fin, then this is acceptable as well.

11.2 Layout Example



www.ti.com.cn ZHCSCB6 – MARCH 2014

12 Device and Documentation Support

12.1 Device Support

12.1.1 Development Support

Texas Instruments has several software tools to aid in the development process including CodeLoder for programming, Clock Design Tool for Loop filter design and phase noise/spur simulation, and the Clock Architect. All these tools are available at www.ti.com.

12.2 Documentation Support

12.2.1 Related Documentation

For the avid reader, the following resources are available at www.ti.com.

Application Note 1879 -- Fractional N Frequency Synthesis

PLL Performance, Simulation, and Design -- by Dean Banerjee

12.3 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 10. Related Links

PARTS	PRODUCT FOLDER SAMPLE and BUY		TECHNICAL DOCUMENTS	TOOLS and SOFTWARE	SUPPORT and COMMUNITY	
LMX2492	Click here	Click here	Click here	Click here	Click here	
LMX2492-Q1	Click here	Click here	Click here	Click here	Click here	

12.4 Trademarks

All trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms and definitions.

13 机械封装和可订购信息

以下页中包括机械封装和可订购信息。 这些信息是针对指定器件可提供的最新数据。 这些数据会在无通知且不对本文档进行修订的情况下发生改变。 要获得这份数据表的浏览器版本,请查阅左侧导航栏。

重要声明

德州仪器(TI) 及其下属子公司有权根据 JESD46 最新标准, 对所提供的产品和服务进行更正、修改、增强、改进或其它更改, 并有权根据 JESD48 最新标准中止提供任何产品和服务。客户在下订单前应获取最新的相关信息, 并验证这些信息是否完整且是最新的。所有产品的销售都遵循在订单确认时所提供的TI 销售条款与条件。

TI 保证其所销售的组件的性能符合产品销售时 TI 半导体产品销售条件与条款的适用规范。仅在 TI 保证的范围内,且 TI 认为 有必要时才会使用测试或其它质量控制技术。除非适用法律做出了硬性规定,否则没有必要对每种组件的所有参数进行测试。

TI 对应用帮助或客户产品设计不承担任何义务。客户应对其使用 TI 组件的产品和应用自行负责。为尽量减小与客户产品和应 用相关的风险,客户应提供充分的设计与操作安全措施。

TI 不对任何 TI 专利权、版权、屏蔽作品权或其它与使用了 TI 组件或服务的组合设备、机器或流程相关的 TI 知识产权中授予 的直接或隐含权限作出任何保证或解释。TI 所发布的与第三方产品或服务有关的信息,不能构成从 TI 获得使用这些产品或服 务的许可、授权、或认可。使用此类信息可能需要获得第三方的专利权或其它知识产权方面的许可,或是 TI 的专利权或其它 知识产权方面的许可。

对于 TI 的产品手册或数据表中 TI 信息的重要部分,仅在没有对内容进行任何篡改且带有相关授权、条件、限制和声明的情况 下才允许进行 复制。TI 对此类篡改过的文件不承担任何责任或义务。复制第三方的信息可能需要服从额外的限制条件。

在转售 TI 组件或服务时,如果对该组件或服务参数的陈述与 TI 标明的参数相比存在差异或虚假成分,则会失去相关 TI 组件 或服务的所有明示或暗示授权,且这是不正当的、欺诈性商业行为。TI 对任何此类虚假陈述均不承担任何责任或义务。

客户认可并同意,尽管任何应用相关信息或支持仍可能由 TI 提供,但他们将独力负责满足与其产品及在其应用中使用 TI 产品 相关的所有法律、法规和安全相关要求。客户声明并同意,他们具备制定与实施安全措施所需的全部专业技术和知识,可预见 故障的危险后果、监测故障及其后果、降低有可能造成人身伤害的故障的发生机率并采取适当的补救措施。客户将全额赔偿因 在此类安全关键应用中使用任何 TI 组件而对 TI 及其代理造成的任何损失。

在某些场合中,为了推进安全相关应用有可能对 TI 组件进行特别的促销。TI 的目标是利用此类组件帮助客户设计和创立其特 有的可满足适用的功能安全性标准和要求的终端产品解决方案。尽管如此,此类组件仍然服从这些条款。

TI 组件未获得用于 FDA Class III(或类似的生命攸关医疗设备)的授权许可,除非各方授权官员已经达成了专门管控此类使 用的特别协议。

只有那些 TI 特别注明属于军用等级或"增强型塑料"的 TI 组件才是设计或专门用于军事/航空应用或环境的。购买者认可并同 意,对并非指定面向军事或航空航天用途的 TI 组件进行军事或航空航天方面的应用,其风险由客户单独承担,并且由客户独 力负责满足与此类使用相关的所有法律和法规要求。

TI 己明确指定符合 ISO/TS16949 要求的产品,这些产品主要用于汽车。在任何情况下,因使用非指定产品而无法达到 ISO/TS16949 要求,TI不承担任何责任。

	产品		应用
数字音频	www.ti.com.cn/audio	通信与电信	www.ti.com.cn/telecom
放大器和线性器件	www.ti.com.cn/amplifiers	计算机及周边	www.ti.com.cn/computer
数据转换器	www.ti.com.cn/dataconverters	消费电子	www.ti.com/consumer-apps
DLP® 产品	www.dlp.com	能源	www.ti.com/energy
DSP - 数字信号处理器	www.ti.com.cn/dsp	工业应用	www.ti.com.cn/industrial
时钟和计时器	www.ti.com.cn/clockandtimers	医疗电子	www.ti.com.cn/medical
接口	www.ti.com.cn/interface	安防应用	www.ti.com.cn/security
逻辑	www.ti.com.cn/logic	汽车电子	www.ti.com.cn/automotive
电源管理	www.ti.com.cn/power	视频和影像	www.ti.com.cn/video
微控制器 (MCU)	www.ti.com.cn/microcontrollers		
RFID 系统	www.ti.com.cn/rfidsys		
OMAP应用处理器	www.ti.com/omap		
无线连通性	www.ti.com.cn/wirelessconnectivity	德州仪器在线技术支持社区	www.deyisupport.com

邮寄地址: 上海市浦东新区世纪大道1568 号,中建大厦32 楼邮政编码: 200122 Copyright © 2014, 德州仪器半导体技术(上海)有限公司



PACKAGE OPTION ADDENDUM

20-May-2014

PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty		Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
LMX2492QRTWRQ1	ACTIVE	WQFN	RTW	24	1000	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	-40 to 125	X2492Q	Samples
LMX2492QRTWTQ1	ACTIVE	WQFN	RTW	24	250	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	-40 to 125	X2492Q	Samples
LMX2492RTWR	ACTIVE	WQFN	RTW	24	1000	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	-40 to 85	X2492	Samples
LMX2492RTWT	ACTIVE	WQFN	RTW	24	250	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	-40 to 85	X2492	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

20-May-2014

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF LMX2492, LMX2492-Q1:

Catalog: LMX2492

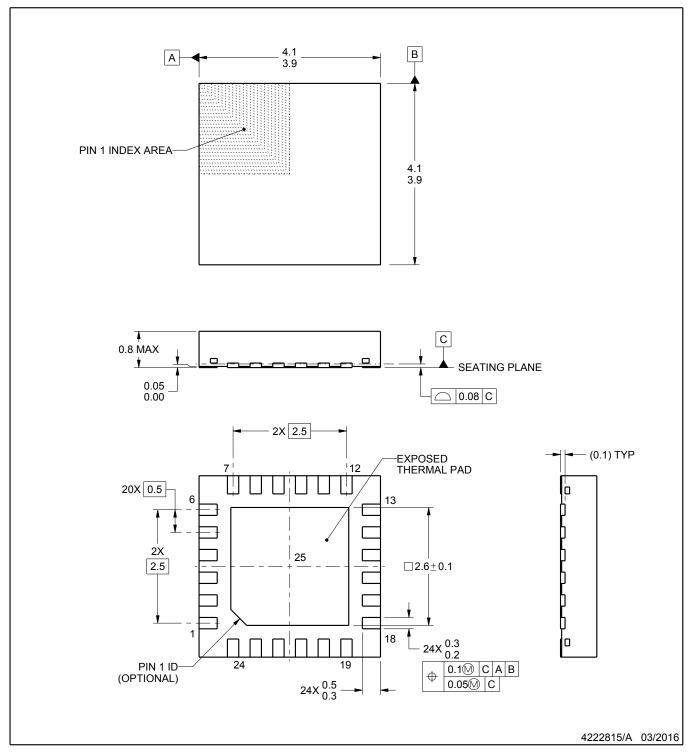
Automotive: LMX2492-Q1

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects



PLASTIC QUAD FLATPACK - NO LEAD

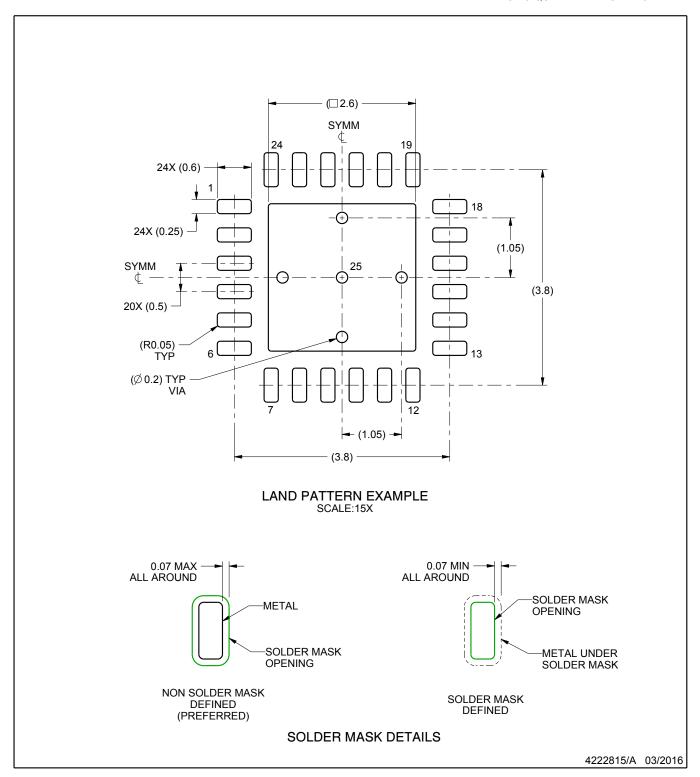


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

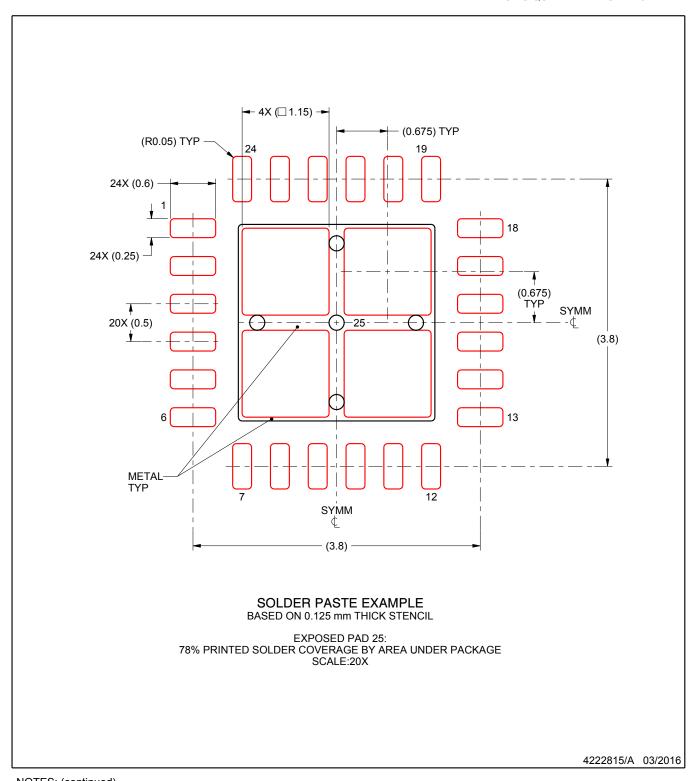


NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



重要声明

德州仪器 (TI) 公司有权按照最新发布的 JESD46 对其半导体产品和服务进行纠正、增强、改进和其他修改,并不再按最新发布的 JESD48 提供任何产品和服务。买方在下订单前应获取最新的相关信息,并验证这些信息是否完整且是最新的。

TI 公布的半导体产品销售条款 (http://www.ti.com/sc/docs/stdterms.htm) 适用于 TI 已认证和批准上市的已封装集成电路产品的销售。另有其他条款可能适用于其他类型 TI 产品及服务的使用或销售。

复制 TI 数据表上 TI 信息的重要部分时,不得变更该等信息,且必须随附所有相关保证、条件、限制和通知,否则不得复制。TI 对该等复制文件不承担任何责任。第三方信息可能受到其它限制条件的制约。在转售 TI 产品或服务时,如果存在对产品或服务参数的虚假陈述,则会失去相关 TI 产品或服务的明示或暗示保证,且构成不公平的、欺诈性商业行为。TI 对此类虚假陈述不承担任何责任。

买方和在系统中整合 TI 产品的其他开发人员(总称"设计人员")理解并同意,设计人员在设计应用时应自行实施独立的分析、评价和判断,且应全权负责并确保应用的安全性,及设计人员的应用(包括应用中使用的所有 TI 产品)应符合所有适用的法律法规及其他相关要求。设计人员就自己设计的应用声明,其具备制订和实施下列保障措施所需的一切必要专业知识,能够 (1) 预见故障的危险后果,(2) 监视故障及其后果,以及 (3) 降低可能导致危险的故障几率并采取适当措施。设计人员同意,在使用或分发包含 TI 产品的任何应用前,将彻底测试该等应用和和该等应用所用 TI 产品的功能而设计。

TI 提供技术、应用或其他设计建议、质量特点、可靠性数据或其他服务或信息,包括但不限于与评估模块有关的参考设计和材料(总称"TI 资源"),旨在帮助设计人员开发整合了 TI 产品的 应用, 如果设计人员(个人,或如果是代表公司,则为设计人员的公司)以任何方式下载、访问或使用任何特定的 TI 资源,即表示其同意仅为该等目标,按照本通知的条款使用任何特定 TI 资源。

TI 所提供的 TI 资源,并未扩大或以其他方式修改 TI 对 TI 产品的公开适用的质保及质保免责声明;也未导致 TI 承担任何额外的义务或责任。TI 有权对其 TI 资源进行纠正、增强、改进和其他修改。除特定 TI 资源的公开文档中明确列出的测试外,TI 未进行任何其他测试。

设计人员只有在开发包含该等 TI 资源所列 TI 产品的 应用时,才被授权使用、复制和修改任何相关单项 TI 资源。但并未依据禁止反言原则或其他法理授予您任何TI知识产权的任何其他明示或默示的许可,也未授予您 TI 或第三方的任何技术或知识产权的许可,该等产权包括但不限于任何专利权、版权、屏蔽作品权或与使用TI产品或服务的任何整合、机器制作、流程相关的其他知识产权。涉及或参考了第三方产品或服务的信息不构成使用此类产品或服务的许可或与其相关的保证或认可。使用 TI 资源可能需要您向第三方获得对该等第三方专利或其他知识产权的许可。

TI 资源系"按原样"提供。TI 兹免除对资源及其使用作出所有其他明确或默认的保证或陈述,包括但不限于对准确性或完整性、产权保证、无屡发故障保证,以及适销性、适合特定用途和不侵犯任何第三方知识产权的任何默认保证。TI 不负责任何申索,包括但不限于因组合产品所致或与之有关的申索,也不为或对设计人员进行辩护或赔偿,即使该等产品组合已列于 TI 资源或其他地方。对因 TI 资源或其使用引起或与之有关的任何实际的、直接的、特殊的、附带的、间接的、惩罚性的、偶发的、从属或惩戒性损害赔偿,不管 TI 是否获悉可能会产生上述损害赔偿,TI 概不负责。

除 TI 己明确指出特定产品已达到特定行业标准(例如 ISO/TS 16949 和 ISO 26262)的要求外,TI 不对未达到任何该等行业标准要求而承担任何责任。

如果 TI 明确宣称产品有助于功能安全或符合行业功能安全标准,则该等产品旨在帮助客户设计和创作自己的 符合 相关功能安全标准和要求的应用。在应用内使用产品的行为本身不会 配有 任何安全特性。设计人员必须确保遵守适用于其应用的相关安全要求和 标准而设计。设计人员不可将任何 TI 产品用于关乎性命的医疗设备,除非已由各方获得授权的管理人员签署专门的合同对此类应用专门作出规定。关乎性命的医疗设备是指出现故障会导致严重身体伤害或死亡的医疗设备(例如生命保障设备、心脏起搏器、心脏除颤器、人工心脏泵、神经刺激器以及植入设备)。此类设备包括但不限于,美国食品药品监督管理局认定为 III 类设备的设备,以及在美国以外的其他国家或地区认定为同等类别设备的所有医疗设备。

TI 可能明确指定某些产品具备某些特定资格(例如 Q100、军用级或增强型产品)。设计人员同意,其具备一切必要专业知识,可以为自己的应用选择适合的 产品, 并且正确选择产品的风险由设计人员承担。设计人员单方面负责遵守与该等选择有关的所有法律或监管要求。

设计人员同意向 TI 及其代表全额赔偿因其不遵守本通知条款和条件而引起的任何损害、费用、损失和/或责任。

邮寄地址: 上海市浦东新区世纪大道 1568 号中建大厦 32 楼,邮政编码: 200122 Copyright © 2018 德州仪器半导体技术(上海)有限公司